ABTS-M ™

Advanced Burn-In & Test System

Cost-effective, reliable and highly configurable system designed to address memory burn-in and test

System Benefits:

- Low Cost of Ownership
  - 72 burn-in board slots (450mm x 570mm BIBs)
  - Up to 28,512 memory devices
  - Small footprint
  - No side access required
  - Highly efficient power delivery
  - Low-power standby mode
- High Reliability and Uptime
  - Redundant architecture
  - Hot-swap electronics and power supplies
- Addresses Diverse Needs
  - Burn-in and test of all DRAM, Flash & SRAM
- Highly Configurable for Production and Engineering
- Cassette Handling of BIBs

" Setting the Test Standard for Tomorrow "

QUALITY SYSTEM CERTIFICATION
DNV·GL
ISO 9001

AEHR TEST SYSTEMS